

# N-Channel Enhancement Mode Power MOSFET

### DESCRIPTION

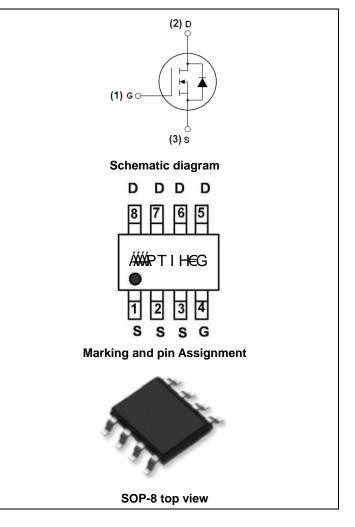
The  $\not$  T I HeG uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

## **GENERAL FEATURES**

- ●V<sub>DS</sub> =30V,I<sub>D</sub> = $\ddot{G}$  A R<sub>DS(ON)</sub> < I ÈmΩ @ V<sub>GS</sub>=10V R<sub>DS(ON)</sub> < Î ÈmΩ @ V<sub>GS</sub>=5V
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current

#### Application

- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply



#### Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
PTIH€G	ÁAPTIH€GÁÁ	SOP-8	Ø330mm	12mm	2500 units

#### Absolute Maximum Ratings (TA=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	30	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	Ι <sub>D</sub>	27	А
Drain Current-Continuous(T <sub>A</sub> =100 ℃)	I <sub>D</sub> (100℃)	1J	A
Pulsed Drain Current	I <sub>DM</sub>	I <sub>DM</sub> ////////////////////////////////////	
Maximum Power Dissipation	PD	3	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> ,T <sub>STG</sub>	-55 To 150	°C

#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Ambient(Note 2)	R <sub>0JA</sub>	42	°C <b>/W</b>	
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#### Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	30	33	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V -		-	±100	nA
On Characteristics (Note 3)	·		•			
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250µA	1.6 ///// ÈG 1.6 //////// ÈG 1.6 ///////			
		$V_{GS}$ =10V, $I_{D}$ =FHA	- ////////		XXXXXA ÈE	
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =5V, I <sub>D</sub> =FHA	- <i>/‱</i>		mΩ	
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> =5V,I <sub>D</sub> =G A	5	-	-	S
Dynamic Characteristics (Note4)			•			
Input Capacitance	C <sub>lss</sub>		-	2100	-	PF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =15V,V <sub>GS</sub> =0V, F=1.0MHz	-	460	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.0MHZ	-	230	-	PF
Switching Characteristics (Note 4)	·		•			
Turn-on Delay Time	t <sub>d(on)</sub>		-	20	-	nS
Turn-on Rise Time	tr	$V_{DD}$ =10V,I <sub>D</sub> =FHA	-	15	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10V, $R_{GEN}$ =2.7 $\Omega$	-	60	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	10	-	nS
Total Gate Charge	Qg	V -10V/L -10A	-	41	-	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ =10V,I <sub>D</sub> =10A,	-	14	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> =10V	-	11	-	nC
Drain-Source Diode Characteristics			•			
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =FHA	-	-	1.2	V
Diode Forward Current (Note 2)	Is		-	-	Ä	Α

#### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

**2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.

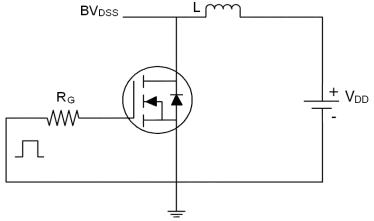
**3.** Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2%.

4. Guaranteed by design, not subject to production

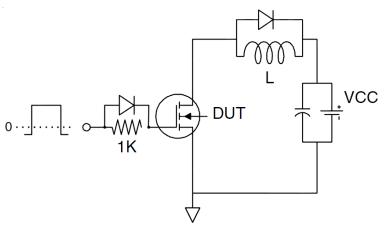
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# **Test circuit**

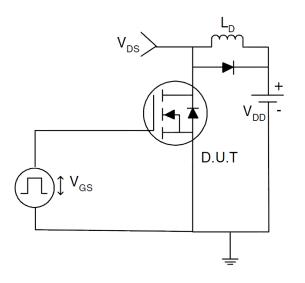
1) E<sub>AS</sub> test Circuits



### 2) Gate charge test Circuit:

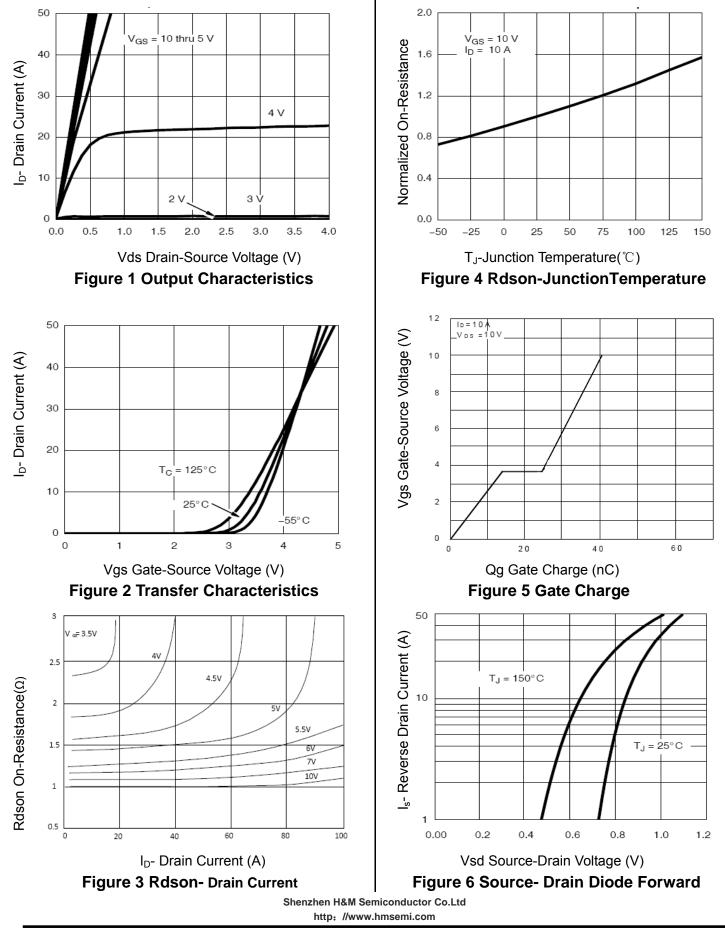


3) Switch Time Test Circuit:

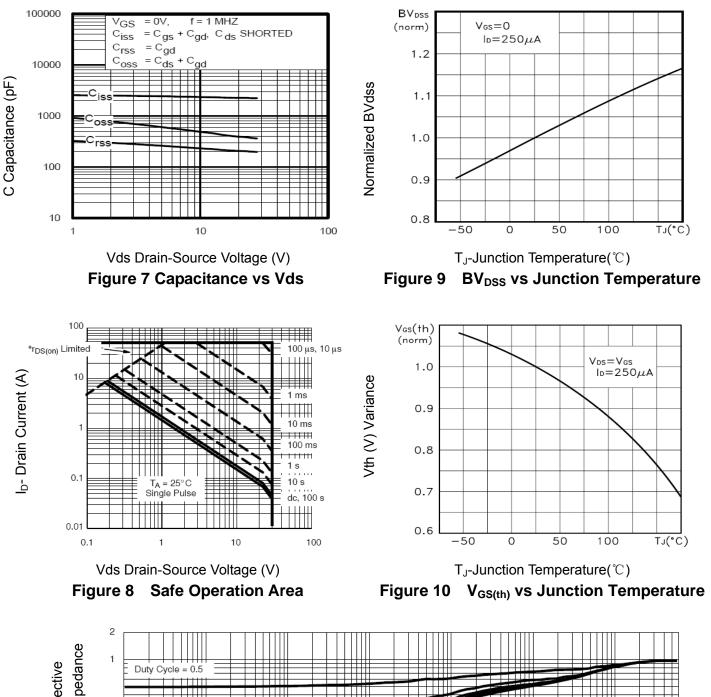


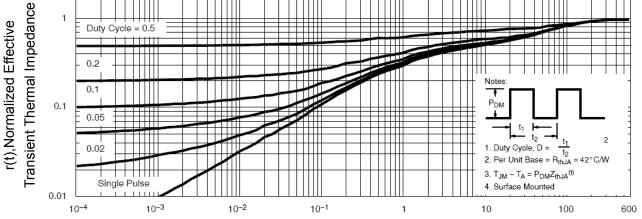
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## **TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (Curves)**



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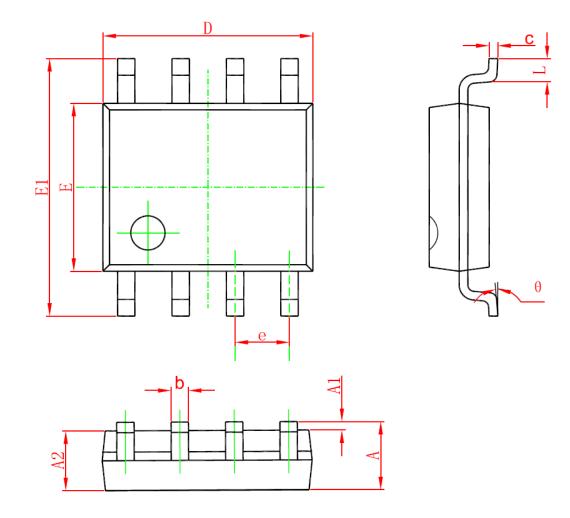
Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance

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# **SOP-8 PACKAGE IN FORMATION**



Cumb a l	Dimensions Ir	n Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	1. 350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0.004	0. 010	
A2	1. 350	1. 550	0.053	0. 061	
b	0. 330	0.510	0.013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
E	3.800	4.000	0. 150	0. 157	
E1	5.800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1. 270	0.016	0. 050	
θ	0°	8°	0°	8°	

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